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AI in Cybersecurity, Volume II

Guest Editors:

Dr. Ayush Goyal

Dr. Avdesh Mishra

Dr. Mais Nijim

Dr. David Hicks

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Message from the Guest Editors

Dear Colleagues,

Cyber defense and security is now an essential field of computer science in light of the ever-increasing threats and attacks on computer infrastructure. Machine learning and artificial intelligence methods are applicable in the detection of cyber threats, such as malware analysis, intrusion detection, injection attacks, etc. There are various algorithms in machine learning and artificial intelligence methods. Additionally, there are several applications of cyber defense, including firewall configuration, packet sniffing, network analysis, and network traffic monitoring. This Special Issue welcomes papers on any of these above mentioned or related topics using or developing machine learning and artificial intelligence algorithms.

Dr. Ayush Goyal Dr. Avdesh Mishra Dr. Mais Nijim Dr. David Hicks Guest Editors











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Editor-in-Chief

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Message from the Editor-in-Chief

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